



In situ beamline analysis and correction of active optics. Erratum

John Sutter,* Simon Alcock and Kawal Sawhney

Diamond Light Source Ltd, Harwell Science and Innovation Campus, Chilton, Didcot, Oxfordshire OX11 0DE, UK. *Correspondence e-mail: john.sutter@diamond.ac.uk

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A correction to one of the equations in the paper by Sutter *et al.* (2012). [*J. Synchrotron Rad.* **19**, 960–968] is made.

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Equation (5) in the paper by Sutter *et al.* (2012) should be

$$B(x) = \frac{(C_1 + C_2)x}{2EI} + \frac{(C_1 - C_2)x^2}{2LEI}. \quad (5)$$

Note the additional factor of 2 in the denominator of the quadratic term on the right-hand side.

References

Sutter, J., Alcock, S. & Sawhney, K. (2012). *J. Synchrotron Rad.* **19**, 960–968.

